

200V N-Channel Enhancement Mode MOSFET

Description

The AP30N20P is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

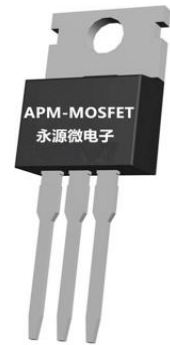
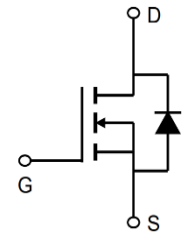
$V_{DS} = 200V$ $I_D = 30A$

$R_{DS(ON)} < 130m\Omega$ @ $V_{GS}=10V$ (Type: 100m Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30N20P	TO-220-3L	AP30N20P XXX YYYY	1000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DS}	Drain-Source Voltage ($V_{GS} = 0V$)	200	V
I_D	Continuous Drain Current	30	A
I_{DM}	Pulsed Drain Current	90	A
V_{GS}	Gate-Source Voltage	± 20	V
EAS	Single Pulse Avalanche Energy	340	mJ
IAR	Avalanche Current	20	A
EAR	Repetitive Avalanche Energy	8.3	mJ
PD	Power Dissipation ($T_C = 25^\circ C$)	104	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^\circ C$
R_{thJC}	Thermal Resistance, Junction-to-Case	1.2	$^\circ C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	60	$^\circ C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	VGS = 0V, ID = 250μA	200	225	--	V
IDSS	Zero Gate Voltage Drain Current	VDS = 200V, VGS = 0V, T _J = 25°C	--	--	5	μA
		VDS = 160V, VGS = 0V, T _J = 125°C	--	--	100	
IGSS	Gate-Source Leakage	VGS = ±20V	--	--	±100	nA
VGS(th)	Gate-Source Threshold Voltage	VDS = VGS, ID = 250μA	2.0	3.0	4.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	VGS = 10V, ID = 9A	--	100	130	mΩ
Ciss	Input Capacitance	VGS = 0V, VDS = 25V, f = 1.0MHz	--	1318	--	pF
Coss	Output Capacitance		--	180	--	
Crss	Reverse Transfer Capacitance		--	75	--	
Qg	Total Gate Charge	VDD = 160V, ID = 18A, VGS = 10V	--	41	--	nC
Qgs	Gate-Source Charge		--	5.5	--	
Qgd	Gate-Drain Charge		--	19.5	--	
td(on)	Turn-on Delay Time	VDD = 100V, ID = 18A, R _G = 25 Ω	--	24	--	ns
tr	Turn-on Rise Time		--	45	--	
td(off)	Turn-off Delay Time		--	101	--	
tf	Turn-off Fall Time		--	95	--	
IS	Continuous Body Diode Current	TC = 25 °C	--	--	18	A
ISM	Pulsed Diode Forward Current		--	--	72	
VSD	Body Diode Voltage	T _J = 25°C, ISD = 18A, VGS = 0V	--	--	1.4	V
trr	Reverse Recovery Time	VGS = 0V, IS = 18A, diF/dt = 100A/μs	--	230	--	ns
Qrr	Reverse Recovery Charge		--	1.8	--	μC

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The EAS data shows Max. rating . I_{AS} = 20A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25 °C
- 3、 The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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Typical Characteristics

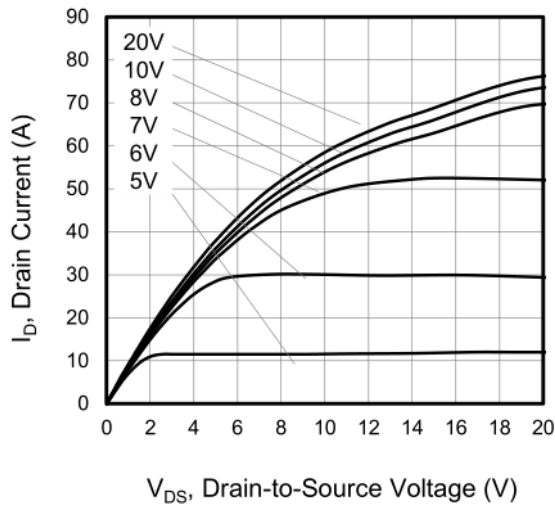


Figure 1. Output Characteristics ($T_J = 25^\circ\text{C}$)

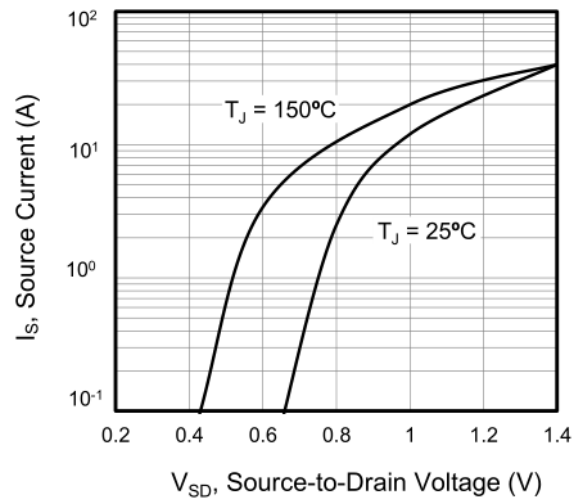


Figure 2. Body Diode Forward Voltage

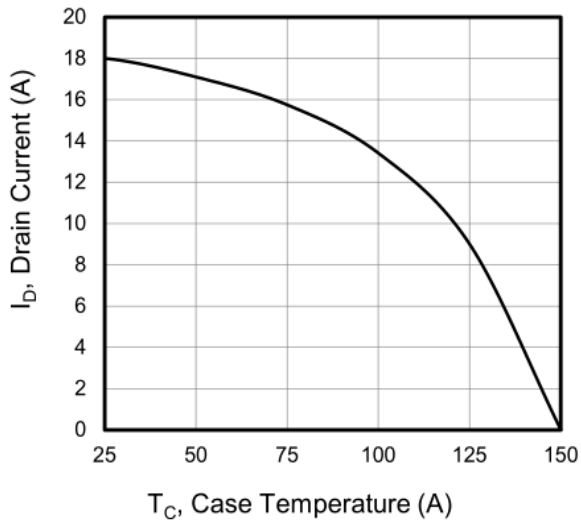


Figure 3. Drain Current vs. Temperature

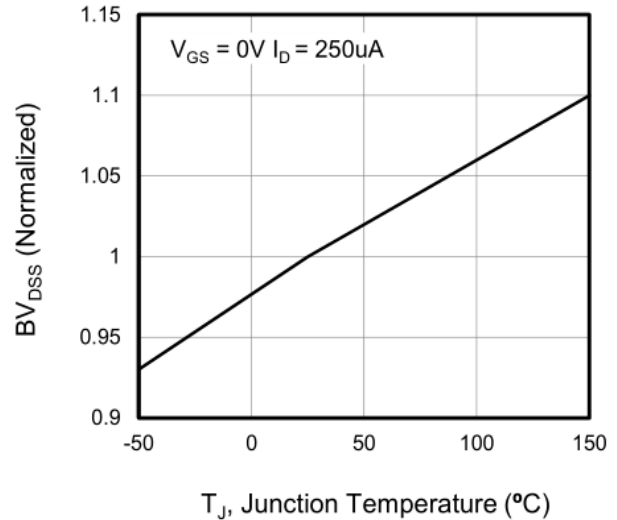


Figure 4. BV_{DSS} Variation vs. Temperature

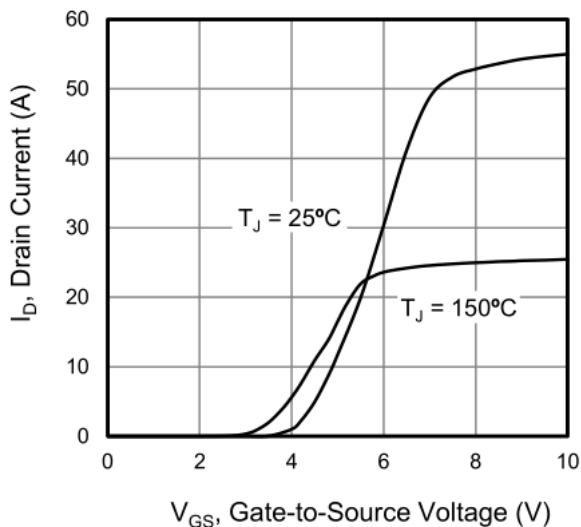


Figure 5. Transfer Characteristics

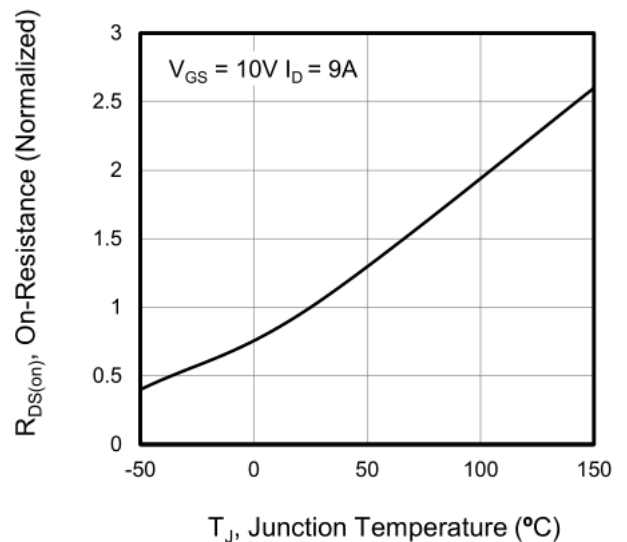
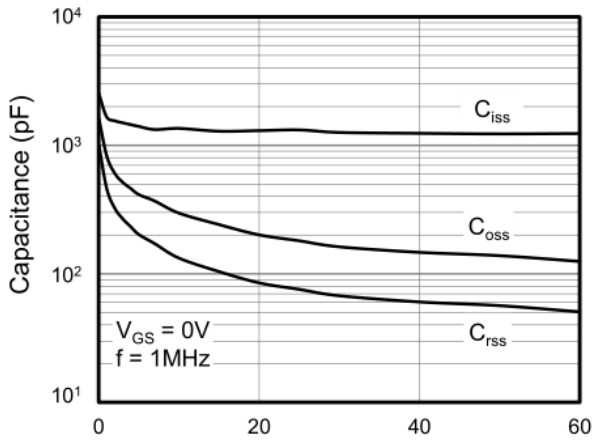


Figure 6. On-Resistance vs. Temperature

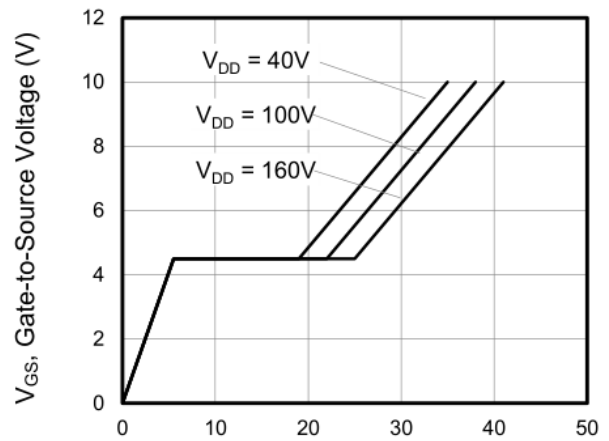


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V_{DS} , Drain-to-Source Voltage (V)

Figure 7. Capacitance



Q_g , Total Gate Charge (nC)

Figure 8. Gate Charge

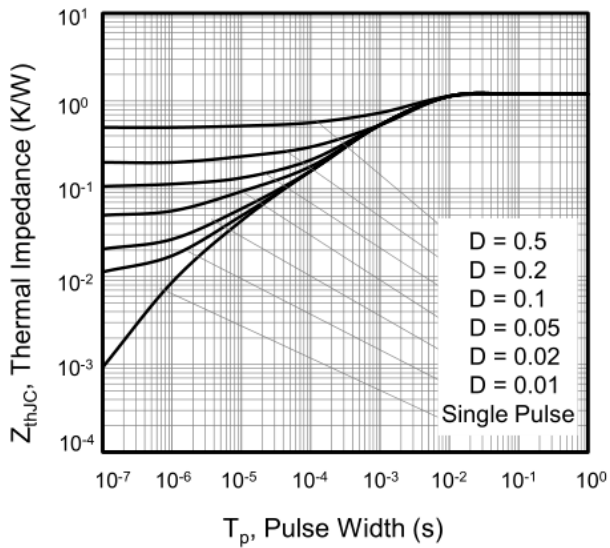
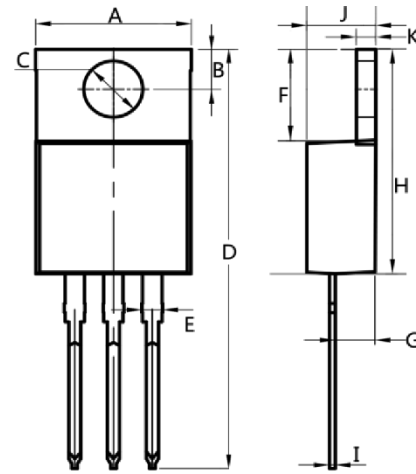


Figure 10. Transient Thermal Impedance

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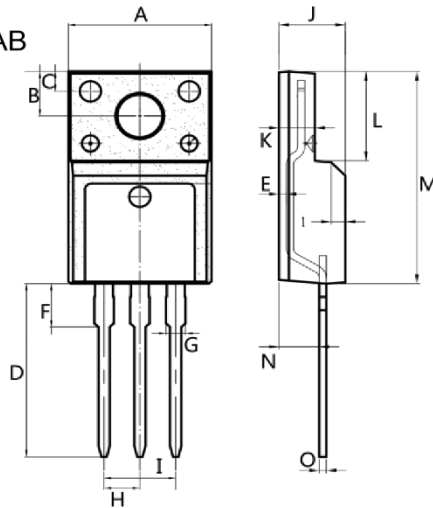
TO-220AB



Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter

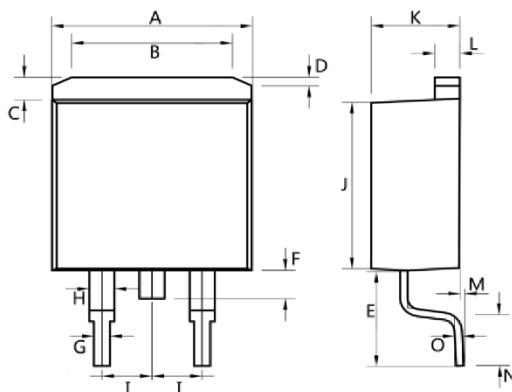
ITO-220AB



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ 2.54	
I	Typ 5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter

TO-263



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ 2.54	
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter

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Edition	Date	Change
Rve1.0	2021/7/31	Initial release

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